# **Power MOSFET**

# 30 V, 64 A, Single N-Channel, WDFN8

### **Features**

- Integrated Schottky Diode
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb-Free and are RoHS Compliant

### **Applications**

- CPU Power Delivery
- Synchronous Rectification for DC-DC Converters
- Low Side Switching
- Telecom Secondary Side Rectification

### MAXIMUM RATINGS (T, = 25°C unless otherwise stated)

		unicos otnerw		ı	ī
Param	Symbol	Value	Unit		
Drain-to-Source Voltage	$V_{DSS}$	30	V		
Gate-to-Source Voltage			$V_{GS}$	±20	V
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	22	Α
Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 85°C		15.9	
Power Dissipation $R_{\theta JA}$ (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.69	W
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	32.4	Α
Current R <sub>θJA</sub> ≤ 10 s (Note 1)		T <sub>A</sub> = 85°C		23.4	
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$	Steady	T <sub>A</sub> = 25°C	P <sub>D</sub>	5.85	W
Continuous Drain	State	T <sub>A</sub> = 25°C	I <sub>D</sub>	16.3	Α
Current R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 85°C		11.7	
Power Dissipation R <sub>0JA</sub> (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	1.47	W
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	64	Α
Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 85°C		46	
Power Dissipation R <sub>0</sub> JC (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	22.73	W
Pulsed Drain Current	T <sub>A</sub> = 25°	C, t <sub>p</sub> = 10 μs	$I_{DM}$	192	Α
Operating Junction and S	T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C		
Source Current (Body Did	I <sub>S</sub>	32	Α		
Drain to Source dV/dt	dV/dt	6.0	V/ns		
Single Pulse Drain-to-So $(T_J = 25^{\circ}C, V_{DD} = 50 \text{ V}, \text{ I}_L = 32 \text{ A}_{pk}, L = 0.1 \text{ mH}, F$	E <sub>AS</sub>	52	mJ		
Lead Temperature for So (1/8" from case for 10 s)	TL	260	°C		

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Surface-mounted on FR4 board using 1 sq-in pad, 2 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size of 90 mm<sup>2</sup>.

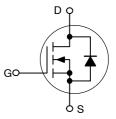


## ON Semiconductor®

### http://onsemi.com

V <sub>(BR)DSS</sub>	V <sub>(BR)DSS</sub> R <sub>DS(on)</sub> MAX	
30 V	3.5 mΩ @ 10 V	64 A
30 V	5.2 mΩ @ 4.5 V	047

#### **N-Channel MOSFET**

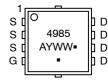




(μ8FL)

CASE 511AB

## **MARKING DIAGRAM**



4985 = Specific Device Code Α = Assembly Location

= Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>				
NTTFS4985NFTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel				
NTTFS4985NFTWG	WDFN8 (Pb-Free)	5000 / Tape & Reel				

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	5.5	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{ heta JA}$	46.4	
Junction-to-Ambient - Steady State (Note 4)	$R_{ heta JA}$	84.8	
Junction–to–Ambient – (t ≤ 10 s) (Note 3)	$R_{ heta JA}$	21.4	

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•				•	*	•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				15		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V}, \\ V_{DS} = 24 \text{ V}$ $T_{J} = 25^{\circ}\text{C}$				500	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	; = ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 250 μΑ	1.2	1.6	2.3	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.2		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>		I <sub>D</sub> = 20 A		2.8	3.5	mΩ
		V <sub>GS</sub> = 10 V	I <sub>D</sub> = 10 A		2.8		1
	V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 20 A		4.16	5.2	1	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 10 A		4.13		
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 10 A			34		S
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V, f = 1.0 MHz, V <sub>DS</sub> = 15 V			2075		pF
Output Capacitance	C <sub>oss</sub>				876		
Reverse Transfer Capacitance	C <sub>rss</sub>				46		
Total Gate Charge	Q <sub>G(TOT)</sub>				13.6		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	\	IT. V. I		2.0		
Gate-to-Source Charge	$Q_{GS}$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 1$	15 V, I <sub>D</sub> = 20 A		5.8		
Gate-to-Drain Charge	$Q_{GD}$				4.1		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 1	5 V, I <sub>D</sub> = 20 A		29.4		nC
SWITCHING CHARACTERISTICS (No	ote 6)						
Turn-On Delay Time	t <sub>d(on)</sub>				11		ns
Rise Time	t <sub>r</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			24		
Turn-Off Delay Time	t <sub>d(off)</sub>				20		7
Fall Time	t <sub>f</sub>				5.4		1
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			8.5		ns
Rise Time	t <sub>r</sub>				24		1
Turn-Off Delay Time	t <sub>d(off)</sub>				25		
Fall Time	t <sub>f</sub>				4.0		7

<sup>5.</sup> Pulse Test: pulse width = 300  $\mu$ s, duty cycle  $\leq$  2%.

<sup>3.</sup> Surface-mounted on FR4 board using 1 sq-in pad, 2 oz Cu.
4. Surface-mounted on FR4 board using the minimum recommended pad size of 90 mm².

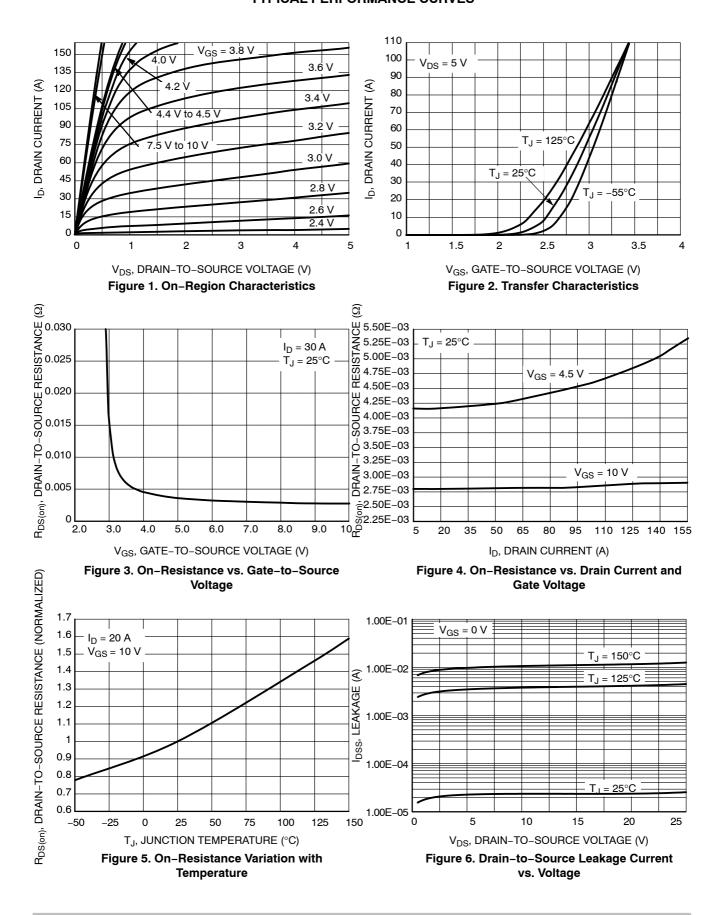
<sup>6.</sup> Switching characteristics are independent of operating junction temperatures.

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

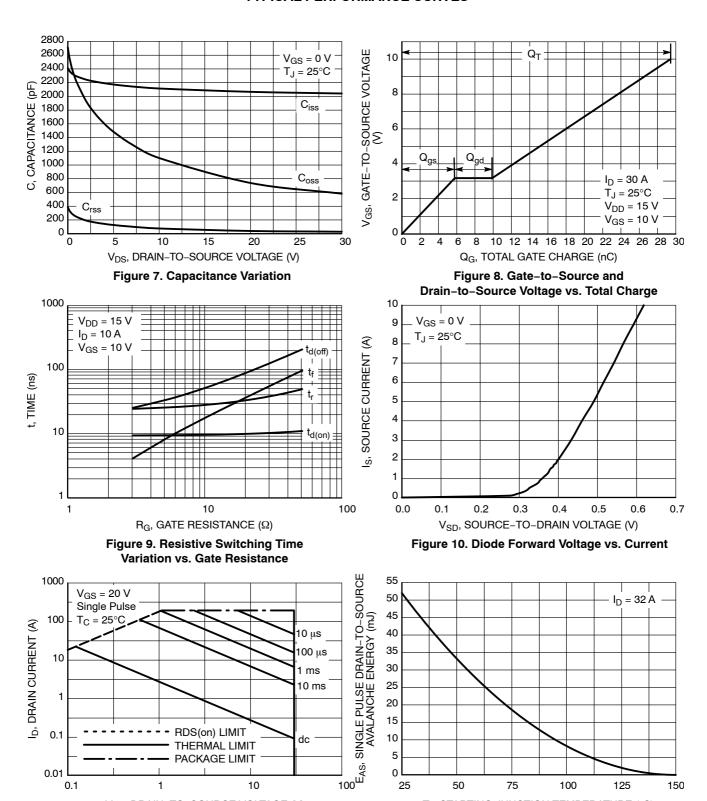
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit		
DRAIN-SOURCE DIODE CHARACTERISTICS									
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.4	0.7	V		
		$V_{GS} = 0 V,$ $I_{S} = 2 A$ $T_{J} = 125^{\circ}C$			0.33		1		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS}$ = 0 V, $d_{IS}/d_t$ = 100 A/ $\mu$ s, $I_S$ = 2 A			35.7		ns		
Charge Time	ta				18.2				
Discharge Time	t <sub>b</sub>				17.5				
Reverse Recovery Charge	Q <sub>RR</sub>				32		nC		
PACKAGE PARASITIC VALUES									
Source Inductance	L <sub>S</sub>	T <sub>A</sub> = 25°C			0.65		nH		
Drain Inductance	L <sub>D</sub>				0.20		1		
Gate Inductance	L <sub>G</sub>				1.5		1		
Gate Resistance	R <sub>G</sub>				1.0		Ω		

<sup>5.</sup> Pulse Test: pulse width = 300  $\mu$ s, duty cycle  $\leq$  2%.
6. Switching characteristics are independent of operating junction temperatures.

### TYPICAL PERFORMANCE CURVES



### TYPICAL PERFORMANCE CURVES



V<sub>DS</sub>, DRAIN-TO-SOURCE VOLTAGE (V) Figure 11. Maximum Rated Forward Biased Safe Operating Area

0.1

T<sub>J</sub>, STARTING JUNCTION TEMPERATURE (°C) Figure 12. Maximum Avalanche Energy vs. **Starting Junction Temperature** 

100

150

75

25

50

# **TYPICAL PERFORMANCE CURVES**

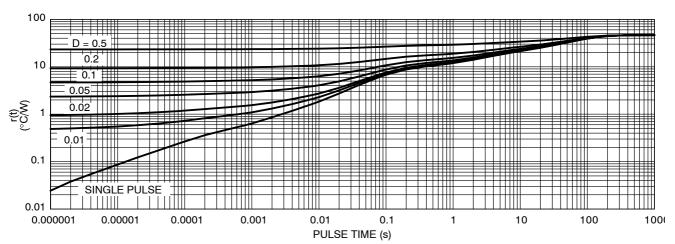
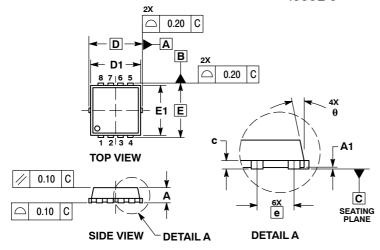


Figure 13. Thermal Response

### **PACKAGE DIMENSIONS**

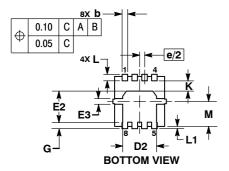
### WDFN8 3.3x3.3, 0.65P CASE 511AB **ISSUE C**



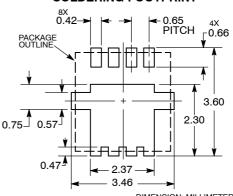
#### NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETERS.
  DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS				<b>INCHES</b>		
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D		3.30 BSC	;	0	.130 BSC	)	
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E		3.30 BSC	;	0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е		0.65 BSC			0.026 BSC		
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.64			0.025			
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
М	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	



# SOLDERING FOOTPRINT\*



**DIMENSION: MILLIMETERS** 

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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